

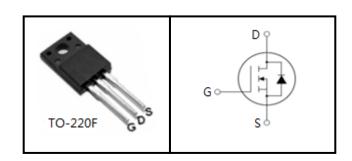
## **650V N-Channel MOSFET**

#### **FEATURES**

- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

#### **APPLICATIONS**

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)



Device Marking and Package Information				
Device	vice Package			
CS10N65FF	TO-220F	CS10N65FF		

<b>Absolute Maximum Ratings</b> T <sub>C</sub> = 25°C, unless otherwise noted							
Parameter	Symbol	Value	Unit				
Farameter		TO-220F	Unit				
Drain-Source Voltage (V <sub>GS</sub> = 0V)	$V_{\rm DSS}$	650	V				
Continuous Drain Current	I <sub>D</sub>	10	Α				
Pulsed Drain Current (note1)	I <sub>DM</sub>	40	Α				
Gate-Source Voltage	$V_{GSS}$	±30	>				
Single Pulse Avalanche Energy (note2)	E <sub>AS</sub>	304	mJ				
Avalanche Current (note1)	I <sub>AS</sub>	7.8	Α				
Repetitive Avalanche Energy (note1)	E <sub>AR</sub>	182.4	mJ				
Power Dissipation (T <sub>C</sub> = 25°C)	$P_{D}$	65	W				
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55~+150	°C				

Thermal Resistance				
Devenueter	Cumbal	Value	Unit	
Parameter	Symbol	TO-220F	Unit	
Thermal Resistance, Junction-to-Case	R <sub>thJC</sub>	1.92	°C/W	
Thermal Resistance, Junction-to-Ambient	$R_{thJA}$	62.5		



<b>Specifications</b> T <sub>J</sub> = 25°C, unless otherwise noted									
Dominion		T . O . III	Value			Unit			
rameter Symbol Test Conditions		Min.	Тур.	Max.					
Static									
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_{D} = 250\mu A$	650			<b>V</b>			
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 650V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	μΑ			
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 30V$			±100	nA			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		4.0	V			
Drain-Source On-Resistance (Note3)	R <sub>DS(on)</sub>	$V_{GS} = 10V, I_{D} = 5.0A$		0.65	0.8	Ω			
Dynamic									
Input Capacitance	C <sub>iss</sub>			1507		pF			
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0V$ , $V_{DS} = 25V$ , f = 1.0MHz		135					
Reverse Transfer Capacitance	C <sub>rss</sub>			3.8					
Internal Gate Resistance	Rg			1.1		Ω			
Total Gate Charge	$Q_g$			28		nC			
Gate-Source Charge	$Q_{gs}$	$V_{DD} = 520V, I_{D} = 10A, V_{GS} = 10V$		7.3					
Gate-Drain Charge	$Q_{gd}$	93 -		10					
Turn-on Delay Time	t <sub>d(on)</sub>			43.3		ns			
Turn-on Rise Time	t <sub>r</sub>	V <sub>DD</sub> = 325V, I <sub>D</sub> =10A,		17.3					
Turn-off Delay Time	t <sub>d(off)</sub>	$R_G = 25 \Omega$		112					
Turn-off Fall Time	t <sub>f</sub>			35.4					
Drain-Source Body Diode Character	istics								
Continuous Body Diode Current	Is	T 05.00	-		10	А			
Pulsed Diode Forward Current	I <sub>SM</sub>	T <sub>C</sub> = 25 °C			40				
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25^{\circ}\text{C}, I_{SD} = 5\text{A}, V_{GS} = 0\text{V}$			1.2	V			
Reverse Recovery Time	t <sub>rr</sub>	VR=325V,I <sub>S</sub> = 10A,		310		ns			
Reverse Recovery Charge	Q <sub>rr</sub>	di <sub>F</sub> /dt =100A /μs		3.6		μC			

#### Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L=10mH,  $V_{DD}$  = 50V,  $R_G$  = 25  $\Omega$ , Starting  $T_J$  = 25  $^{\circ}C$
- 3. Pulse Test: Pulse width ≤ 300µs, Duty Cycle ≤ 1%



## **Typical Characteristics** $T_J = 25^{\circ}C$ , unless otherwise noted

Figure 1. Output Characteristics ( $T_J = 25^{\circ}C$ )

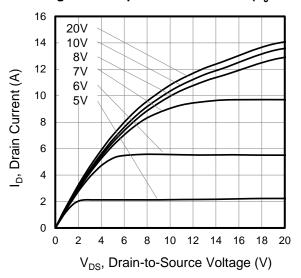
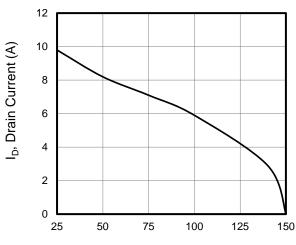


Figure 3. Drain Current vs. Temperature



T<sub>C</sub>, Case Temperature (A)

Figure 5. Transfer Characteristics

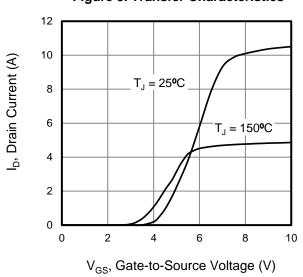


Figure 2. Body Diode Forward Voltage

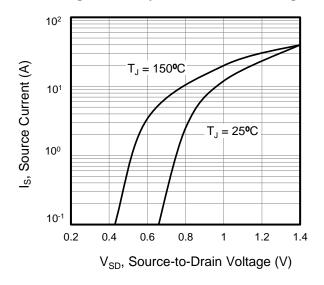


Figure 4. BV<sub>DSS</sub> Variation vs. Temperature

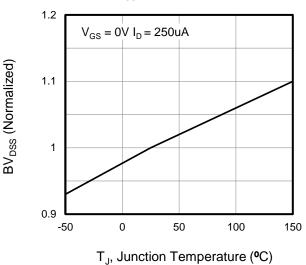
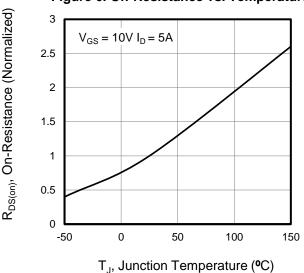


Figure 6. On-Resistance vs. Temperature





### **Typical Characteristics** $T_J = 25^{\circ}\text{C}$ , unless otherwise noted

V<sub>GS</sub>, Gate-to-Source Voltage (V)

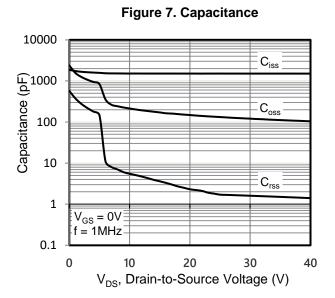


Figure 8. Gate Charge

VDD = 130V
VDD = 325V
VDD = 520V

10
VDD = 520V
10
15
20
25
30

Q<sub>g</sub>, Total Gate Charge (nC)

Figure 9. Transient Thermal Impedance

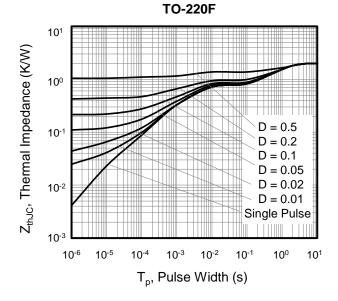




Figure A: Gate Charge Test Circuit and Waveform

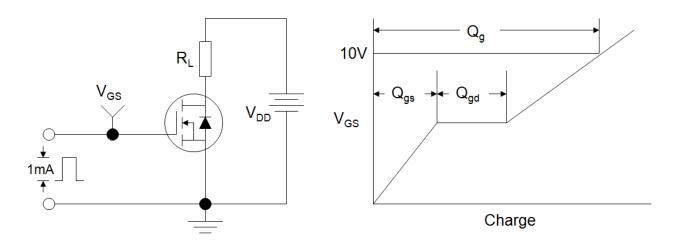


Figure B: Resistive Switching Test Circuit and Waveform

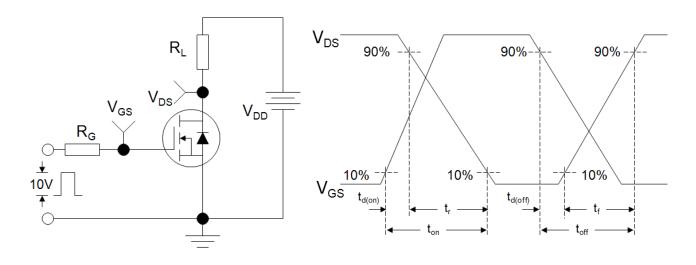
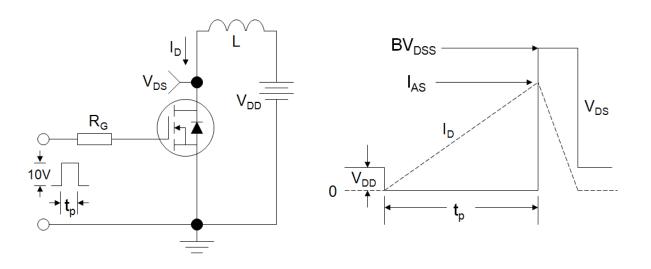
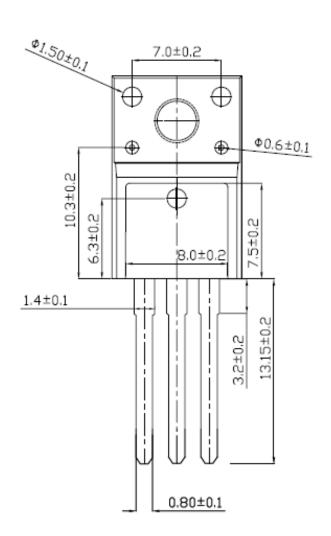


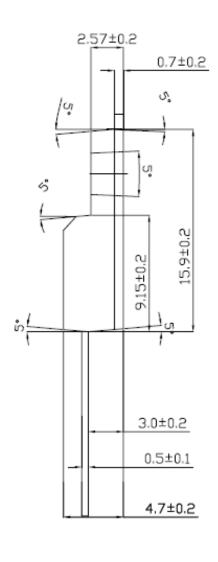
Figure C: Unclamped Inductive Switching Test Circuit and Waveform





# **TO-220F**







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